

2SK2935

Silicon N Channel MOS FET
High Speed Power Switching

HITACHI

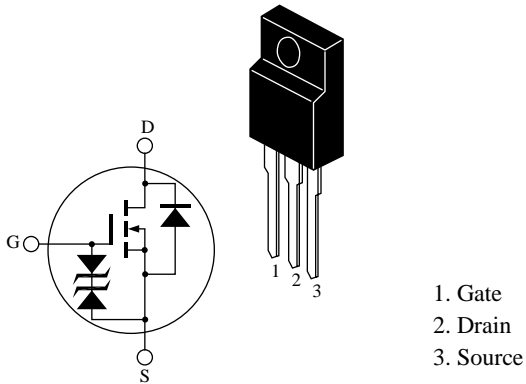
ADE-208-558B (Z)
3rd. Edition
Jun 1998

Features

- Low on-resistance
 $R_{DS} = 0.020 \Omega$ typ.
- High speed switching
- 4V gate drive device can be driven from 5V source

Outline

TO-220CFM



Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

| Item | Symbol | Ratings | Unit |
|--|------------------------|----------------|------------------|
| Drain to source voltage | V_{DSS} | 60 | V |
| Gate to source voltage | V_{GSS} | ± 20 | V |
| Drain current | I_D | 35 | A |
| Drain peak current | $I_{D(pulse)}^{Note1}$ | 140 | A |
| Body-drain diode reverse drain current | I_{DR} | 35 | A |
| Avalanche current | I_{AP}^{Note3} | 35 | A |
| Avalanche energy | E_{AR}^{Note3} | 105 | mJ |
| Channel dissipation | P_{ch}^{Note2} | 30 | W |
| Channel temperature | T_{ch} | 150 | $^\circ\text{C}$ |
| Storage temperature | T_{stg} | -55 to +150 | $^\circ\text{C}$ |

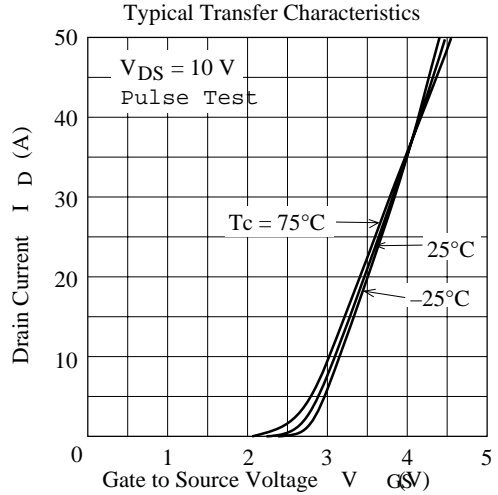
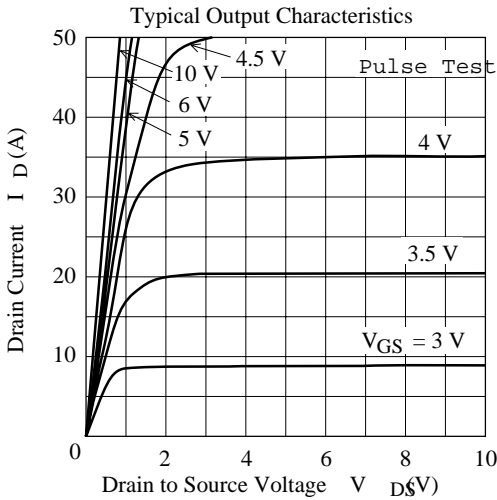
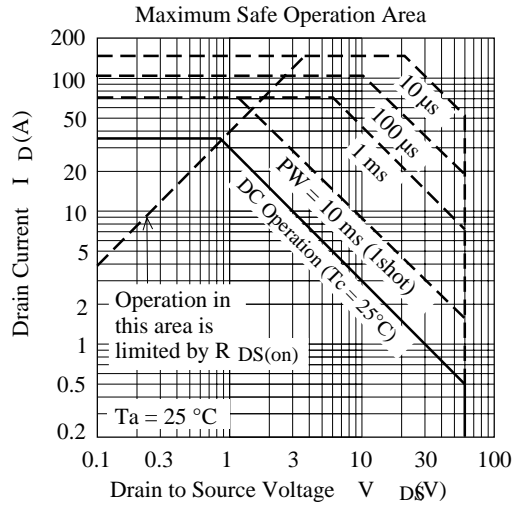
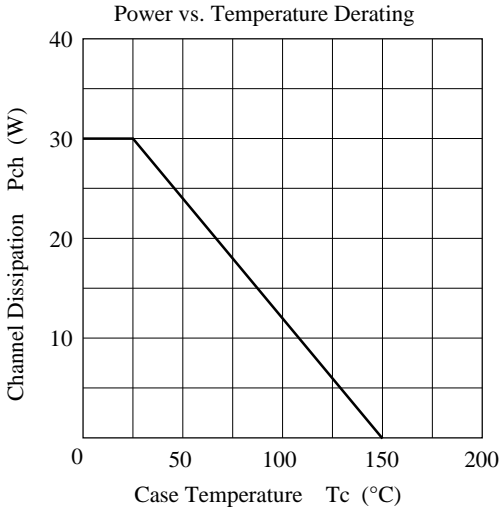
Note: 1. $PW \leq 10\mu\text{s}$, duty cycle $\leq 1\%$
2. Value at $T_c = 25^\circ\text{C}$
3. Value at $T_{ch} = 25^\circ\text{C}$, $R_g \geq 50\Omega$

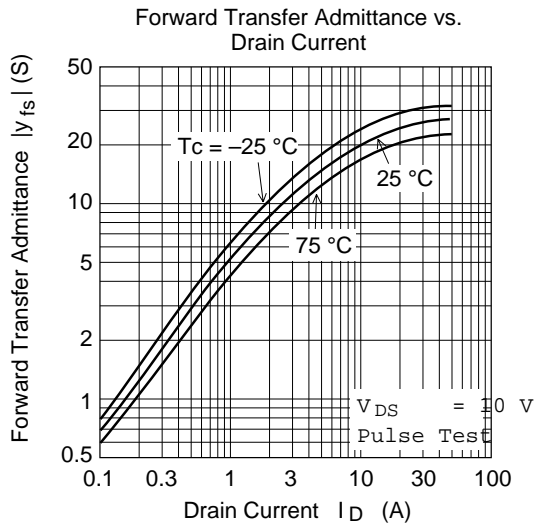
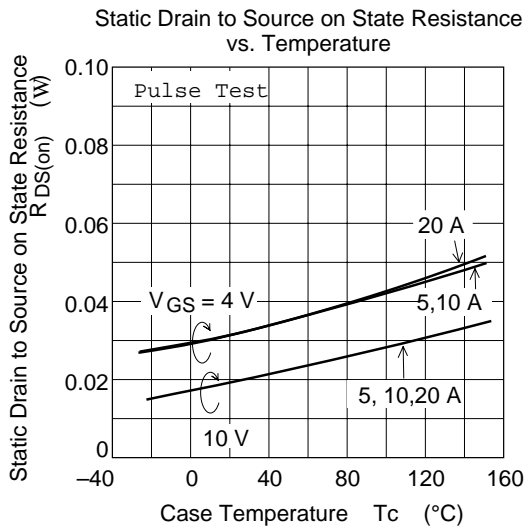
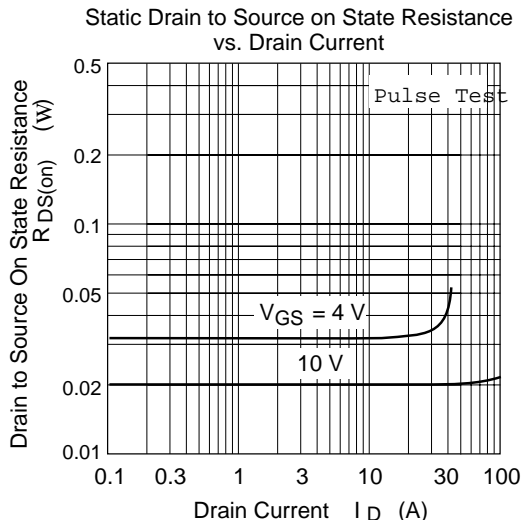
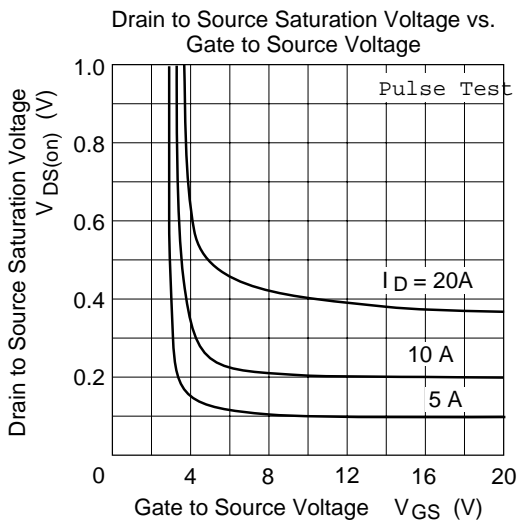
Electrical Characteristics (Ta = 25°C)

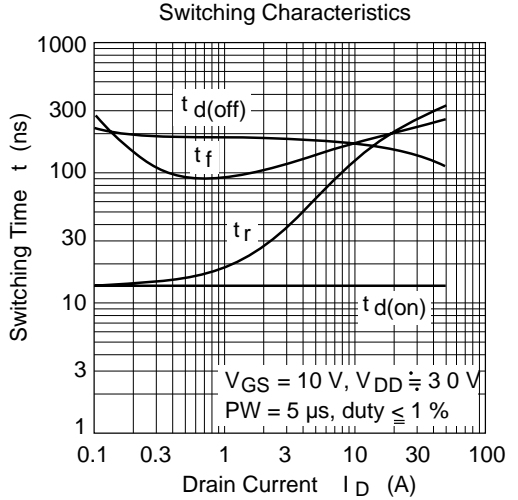
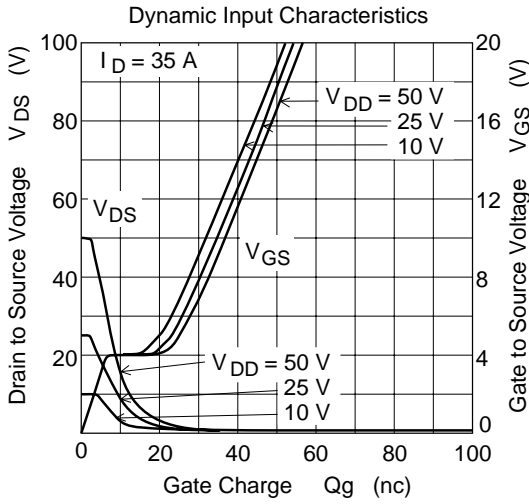
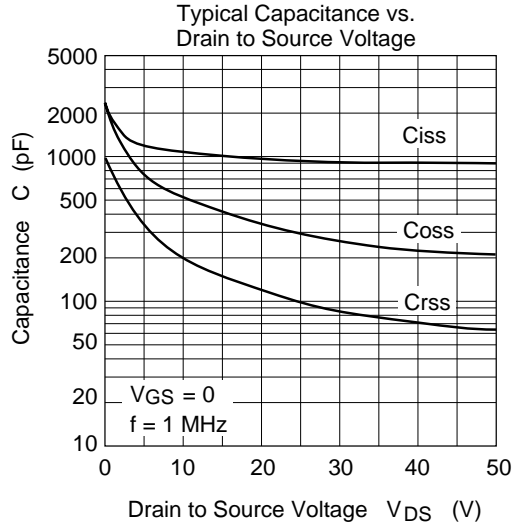
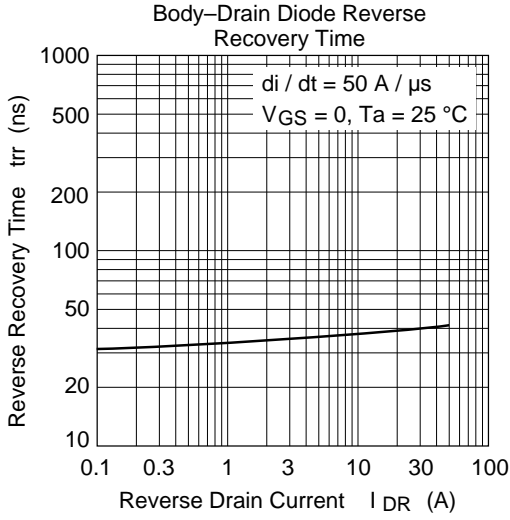
| Item | Symbol | Min | Typ | Max | Unit | Test Conditions |
|--|---------------|----------|-------|----------|---------------|--|
| Drain to source breakdown voltage | $V_{(BR)DSS}$ | 60 | — | — | V | $I_D = 10\text{mA}$, $V_{GS} = 0$ |
| Gate to source breakdown voltage | $V_{(BR)GSS}$ | ± 20 | — | — | V | $I_G = \pm 100\mu\text{A}$, $V_{DS} = 0$ |
| Gate to source leak current | I_{GSS} | — | — | ± 10 | μA | $V_{GS} = \pm 16\text{V}$, $V_{DS} = 0$ |
| Zero gate voltage drain current | I_{DSS} | — | — | 10 | μA | $V_{DS} = 60\text{V}$, $V_{GS} = 0$ |
| Gate to source cutoff voltage | $V_{GS(off)}$ | 1.5 | — | 2.5 | V | $I_D = 1\text{mA}$, $V_{DS} = 10\text{V}$ |
| Static drain to source on state resistance | $R_{DS(on)}$ | — | 0.020 | 0.026 | Ω | $I_D = 15\text{A}$, $V_{GS} = 10\text{V}$ ^{Note4} |
| | $R_{DS(on)}$ | — | 0.032 | 0.050 | Ω | $I_D = 15\text{A}$, $V_{GS} = 4\text{V}$ ^{Note4} |
| Forward transfer admittance | $ y_{fs} $ | 14 | 23 | — | S | $I_D = 15\text{A}$, $V_{DS} = 10\text{V}$ ^{Note4} |
| Input capacitance | C_{iss} | — | 1100 | — | pF | $V_{DS} = 10\text{V}$ |
| Output capacitance | C_{oss} | — | 540 | — | pF | $V_{GS} = 0$ |
| Reverse transfer capacitance | C_{rss} | — | 200 | — | pF | $f = 1\text{MHz}$ |
| Turn-on delay time | $t_{d(on)}$ | — | 15 | — | ns | $I_D = 15\text{A}$, $V_{GS} = 10\text{V}$ |
| Rise time | t_r | — | 180 | — | ns | $R_L = 2\Omega$ |
| Turn-off delay time | $t_{d(off)}$ | — | 175 | — | ns | |
| Fall time | t_f | — | 195 | — | ns | |
| Body-drain diode forward voltage | V_{DF} | — | 0.95 | — | V | $I_F = 35\text{A}$, $V_{GS} = 0$ |
| Body-drain diode reverse recovery time | t_{rr} | — | 40 | — | ns | $I_F = 35\text{A}$, $V_{GS} = 0$ $diF/dt = 50\text{A}/\mu\text{s}$ |

Note: 4. Pulse test

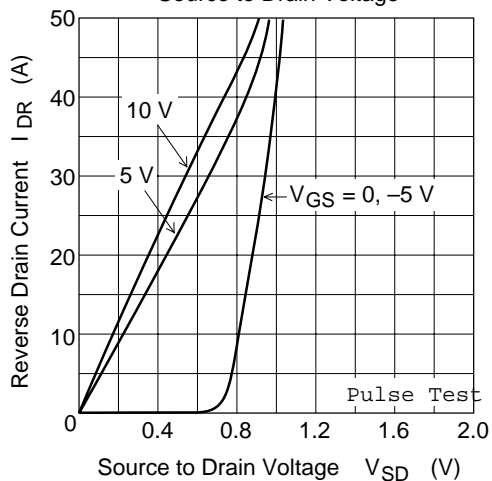
Main Characteristics



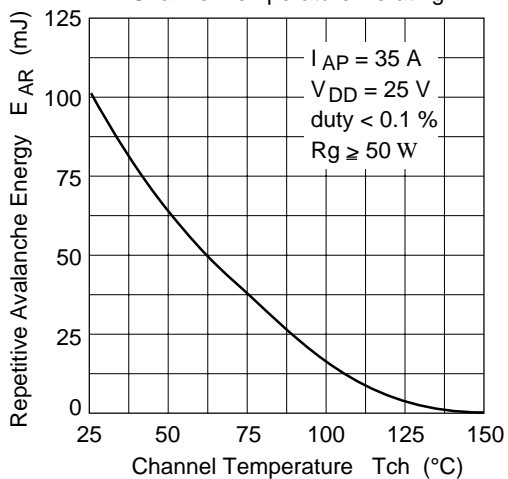




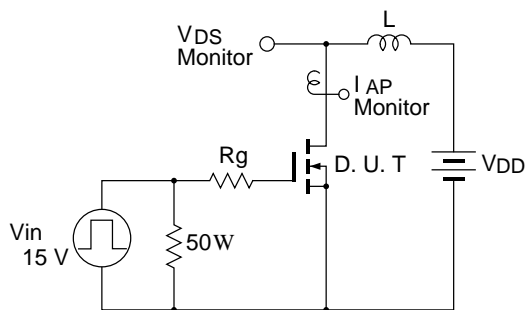
Reverse Drain Current vs. Source to Drain Voltage



Maximum Avalanche Energy vs. Channel Temperature Derating

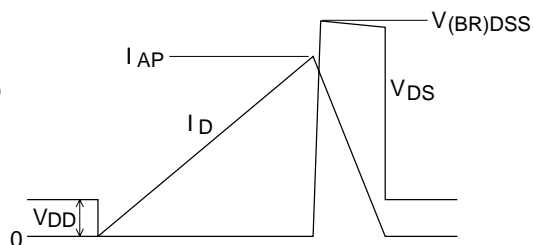


Avalanche Test Circuit

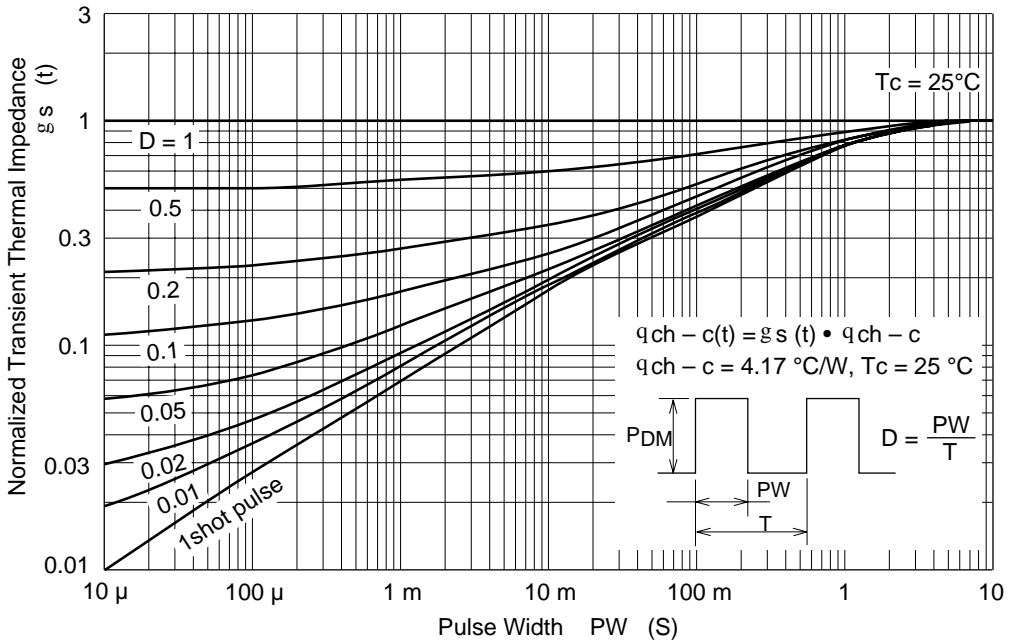


Avalanche Waveform

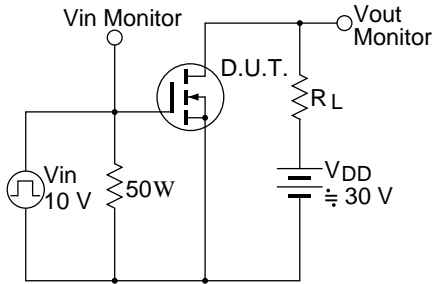
$$E_{AR} = \frac{1}{2} \cdot L \cdot I_{AP}^2 \cdot \frac{V_{DSS}}{V_{DSS} - V_{DD}}$$



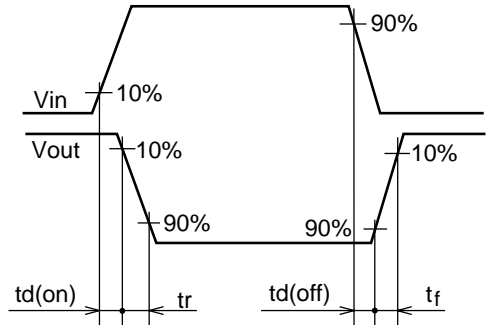
Normalized Transient Thermal Impedance vs. Pulse Width



Switching Time Test Circuit

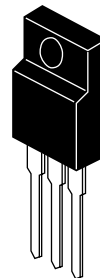
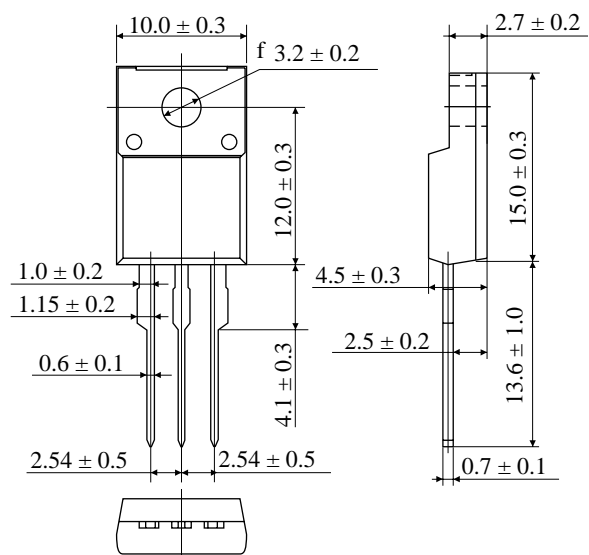


Waveform



Package Dimensions

Unit: mm



| | |
|--------------|-----------|
| Hitachi Code | TO-220CFM |
| EIAJ | — |
| JEDEC | — |

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Hitachi, Ltd.

Semiconductor & Integrated Circuits.
Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan
Tel: Tokyo (03) 3270-2111 Fax: (03) 3270-5109

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For further information write to:

Hitachi Semiconductor
(America) Inc.
179 East Tasman Drive,
San Jose, CA 95134
Tel: <1> (408) 433-1990
Fax: <1>(408) 433-0223

Hitachi Europe GmbH
Electronic components Group
Dornacher Straße 3
D-85622 Feldkirchen, Munich
Germany
Tel: <49> (89) 9 9180-0
Fax: <49> (89) 9 29 30 00

Hitachi Europe Ltd.
Electronic Components Group.
Whitebrook Park
Lower Cookham Road
Maidenhead
Berkshire SL6 8YA, United Kingdom
Tel: <44> (1628) 585000
Fax: <44> (1628) 778322

Hitachi Asia Pte. Ltd.
16 Collyer Quay #20-00
Hitachi Tower
Singapore 049318
Tel: 535-2100
Fax: 535-1533

Hitachi Asia Ltd.
Taipei Branch Office
3F, Hung Kuo Building, No.167,
Tun-Hwa North Road, Taipei (105)
Tel: <886> (2) 2718-3666
Fax: <886> (2) 2718-8180

Hitachi Asia (Hong Kong) Ltd.
Group III (Electronic Components)
7/F., North Tower, World Finance Centre,
Harbour City, Canton Road, Tsim Sha Tsui,
Kowloon, Hong Kong
Tel: <852> (2) 735 9218
Fax: <852> (2) 730 0281
Telex: 40815 HITEC HX

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